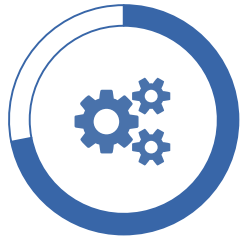




DRIE APPLICATIONS
In Corial 210IL



ICP-RIE equipment for deep etching applications



Wide process range for silicon, silicon carbide, glass, sapphire, and quartz deep etch



Support time-multiplexed processes (Bosch) in conventional dry etch reactor



Smaller wafer pieces up to full 200 mm wafer

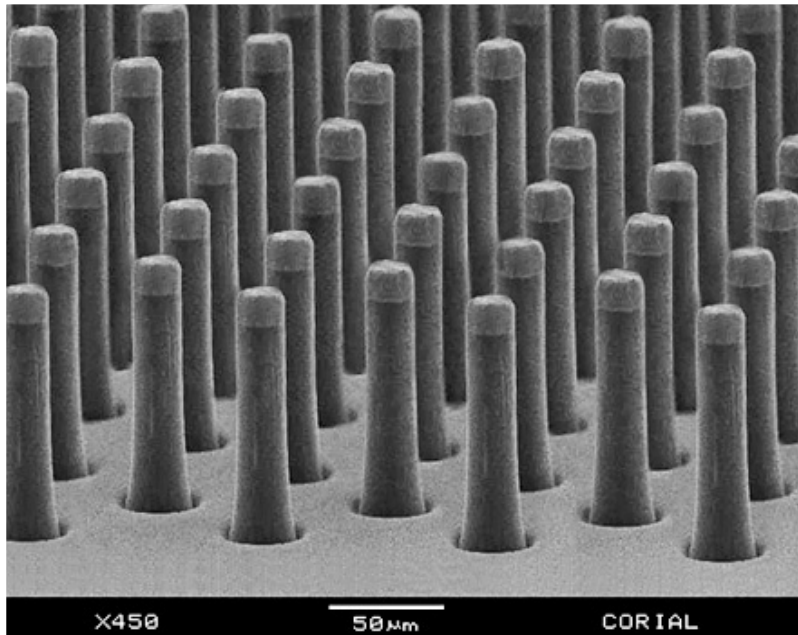


PERFORMANCES GLASS DRIE PROCESS ON CORIAL 210IL



DRIE OF GLASS

7/19/18



> 800 NM/MIN
ETCH RATE

> 15
SELECTIVITY TO Ni
MASK

+30% ETCH RATE
IMPROVEMENT OVER STANDARD
PROCESS

> 100 μm ETCH
DEPTH

± 3 %
UNIFORMITY

CATHODE OPTIMIZED FOR
Ni MASK CLAMPING

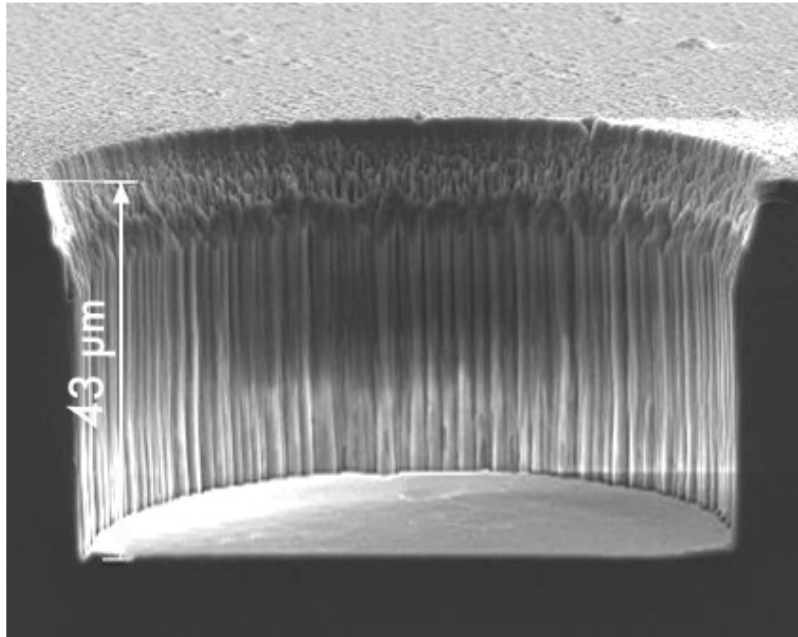
NO ROUGHNESS

PERFORMANCES SIC DRIE PROCESS ON CORIAL 210IL



SIC VIA ETCH PROCESS WITH NI MASK

7/19/18



> 1 400 NM/MIN
ETCH RATE

> 20
SELECTIVITY TO NI
MASK

SMOOTH
SIDEWALLS

> 100
μm ETCH DEPTH

ANISOTROPIC ETCH
PROFILE

± 3 %
UNIFORMITY

PERFORMANCES
SI DRIE PROCESS ON CORIAL 210IL
WITH COSMA PULSE SOFTWARE

COSMA PULSE IS A CONTROL SOFTWARE THAT
BROADENS CONVENTIONAL TOOLS' PROCESS
CAPABILITIES TO ENABLE TIME-MULTIPLEXED
PROCESSES



COSMA PULSE DESCRIPTION

Advanced Process Control



COSMA Monday, February 13, 2017 6:46:00 PM

Editor > Recipe

Name: B_Clean_02Depos_300519 Author: manufacturer Date: 2012-01-30

EPD EXIT

Step 1	Stabilization	Step 2	RF_ON
Time	20 Sec	Time	Sec
End Point	NONE	End Point	NONE
He Clamp Pressure	Measure 4.0 Torr	He Clamp Pressure	Comp To = 4.0 Torr
H2 / O2 sccm	Pulsed	H2 / O2 sccm	Pulsed
BCl3 / 100 sccm	Set To 0.0 sccm	BCl3 / 100 sccm	Set To 0.0 sccm
CF4 / 200 sccm	Pulsed	CF4 / 200 sccm	Pulsed
O2 / 200 sccm	Set To 200.0 sccm	O2 / 200 sccm	Set To 200.0 sccm
He / 150 sccm	Set To 150.0 sccm	He / 150 sccm	Set To 25.0 sccm
RF Feed Power	Pulsed 100W	RF Feed Power	Pulsed 30 Watt
RF Load	Pulsed	RF Load	Pulsed
RF Time	Set To 1170.0 ms	RF Time	Set To 3170.0 ms
LF Feed Power	Set To 0.0 W	LF Feed Power	Set To 0.0 W
LF Load	Set To 500.0	LF Load	Set To 500.0
LF Time	Set To 2045.0	LF Time	Set To 2045.0

USER: admin PROFILE: Manufacturer CONTROL LEVEL: User RELEASE: 3.4.0 (2)

COSMA Monday, February 13, 2017 6:46:00 PM

Editor > Recipe

Name: B_Clean_02Depos_300519 Author: manufacturer Date: 2012-01-30

EPD EXIT

Step 1	Stabilization	Step 2	RF_ON
Time	20 Sec	Time	Sec
End Point	NONE	End Point	NONE
He Clamp Pressure	Measure 4.0 Torr	He Clamp Pressure	Comp To = 4.0 Torr
H2 / O2 sccm	Pulsed	H2 / O2 sccm	Pulsed
BCl3 / 100 sccm	Set To 0.0 sccm	BCl3 / 100 sccm	Set To 0.0 sccm
CF4 / 200 sccm	Pulsed	CF4 / 200 sccm	Pulsed
O2 / 200 sccm	Set To 200.0 sccm	O2 / 200 sccm	Set To 200.0 sccm
He / 150 sccm	Set To 150.0 sccm	He / 150 sccm	Set To 25.0 sccm
RF Feed Power	Pulsed 100W	RF Feed Power	Pulsed 30 Watt
RF Load	Pulsed	RF Load	Pulsed
RF Time	Set To 3000 ms	RF Time	Set To 2000.0 ms
Value 2	Set To 10000 Hz	Value 2	Set To 10000 Hz
Duty Cycle	Set To 50 %	Duty Cycle	Set To 50 %
Delay	Set To 45.0 ms	Delay	Set To 45.0 ms

USER: admin PROFILE: Manufacturer CONTROL LEVEL: User RELEASE: 3.4.0 (2)

EASY
RECIPE PROGRAMATION

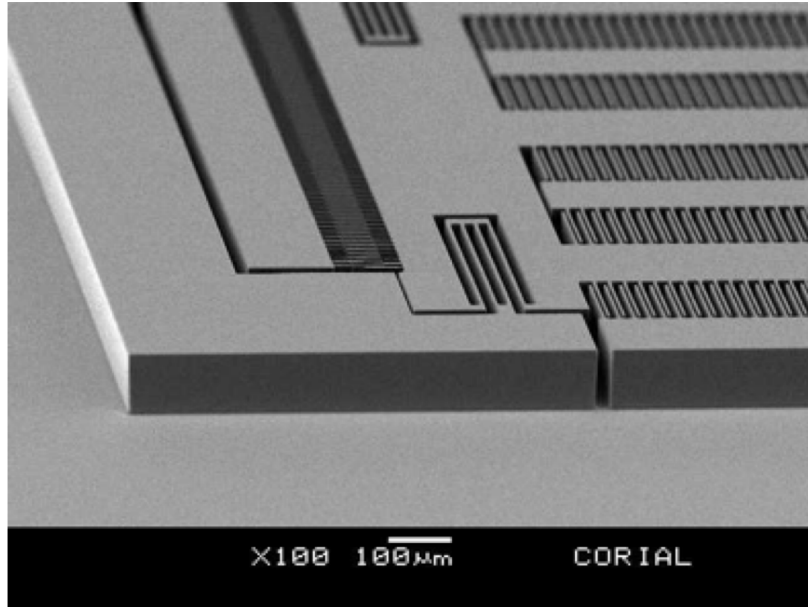
ALL PARAMETERS
CAN BE CONTROLLED AND PULSED

10 ms
DATA ACQUISITION

+/-0,1%
ACCURACY
ON BIAS FINE TUNING



SI DRIE ON CORIAL 210IL



CORIAL Bosch-like process has 3 steps

step 1 - Polymer deposition by C4F8 plasma

step 2 - Polymer etching by SF6 plasma

step 3 - Silicon etching with 20W of RF power, which was used to increase the silicon etching rate

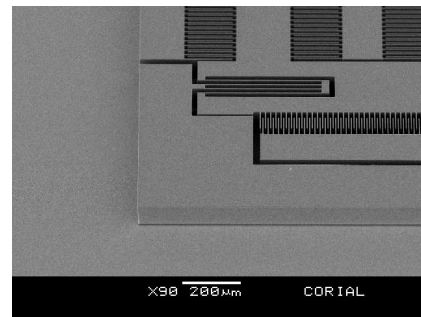
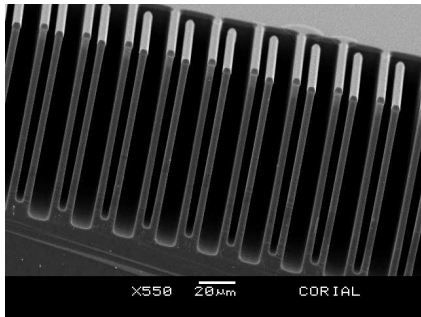
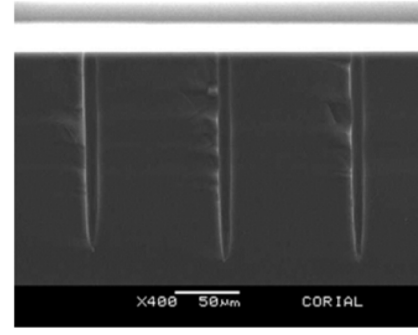
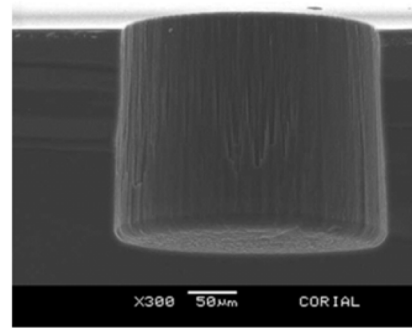
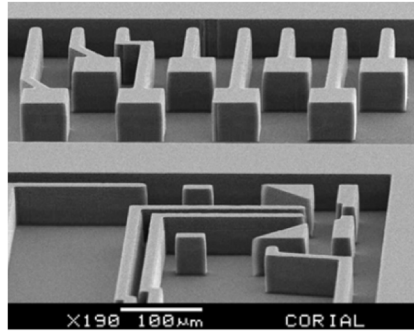
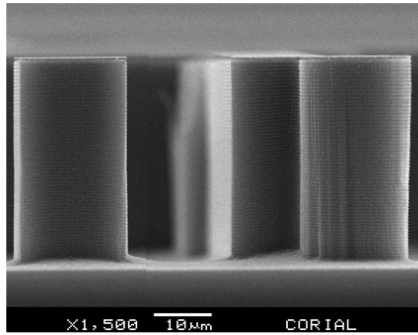
To alternate between each step, **COSMA pulse software** is required for pulsing consecutively C4F8 gas flow, SF6 gas flow, LF and RF power



DRIE OF SILICON



Precise control of the etch profile, fast etch rates, and excellent etch uniformity





DRIE OF SILICON

Various Aspect Ratios

Feature size (μm)	Etched depth (μm)	Aspect ratio	Etch rate ($\mu\text{m}/\text{min}$)	Mask	Selectivity (vs. mask)
$\text{\O}250$	Through wafer	1:2	> 3.0	SiO ₂	330
$\text{\O}100$	515	1:5	> 2.9	PR	85
$\text{\O}20$	280	1:14	> 1.5	SiO ₂	155
$\text{\O}5$	180	1:35	> 1.0	SiO ₂	100

Results obtained with 100 mm wafer, 20% Si open area

SYSTEM DESCRIPTION

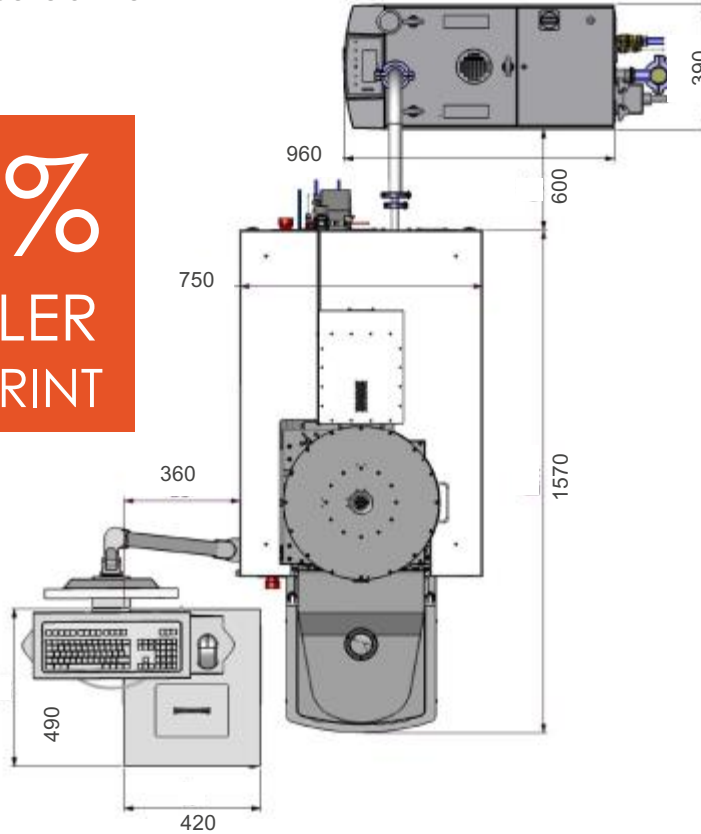
CORIAL 210IL



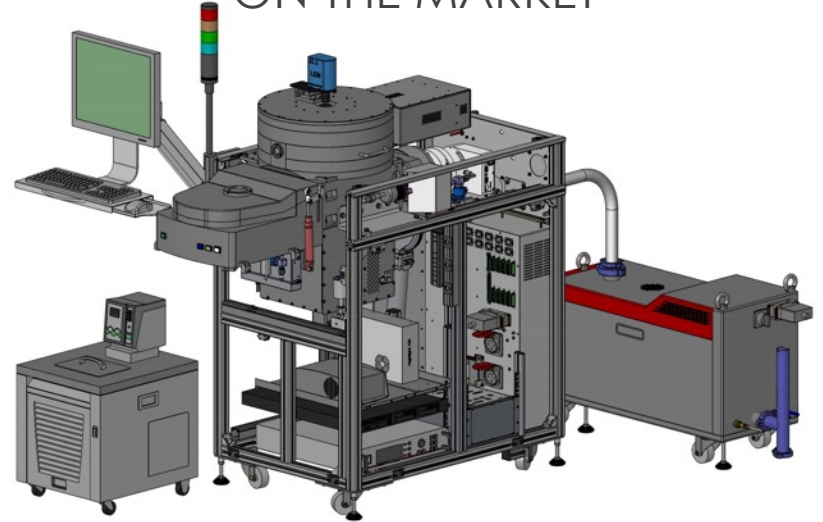
SYSTEM DESCRIPTION

General View

**30 %
SMALLER
FOOTPRINT**



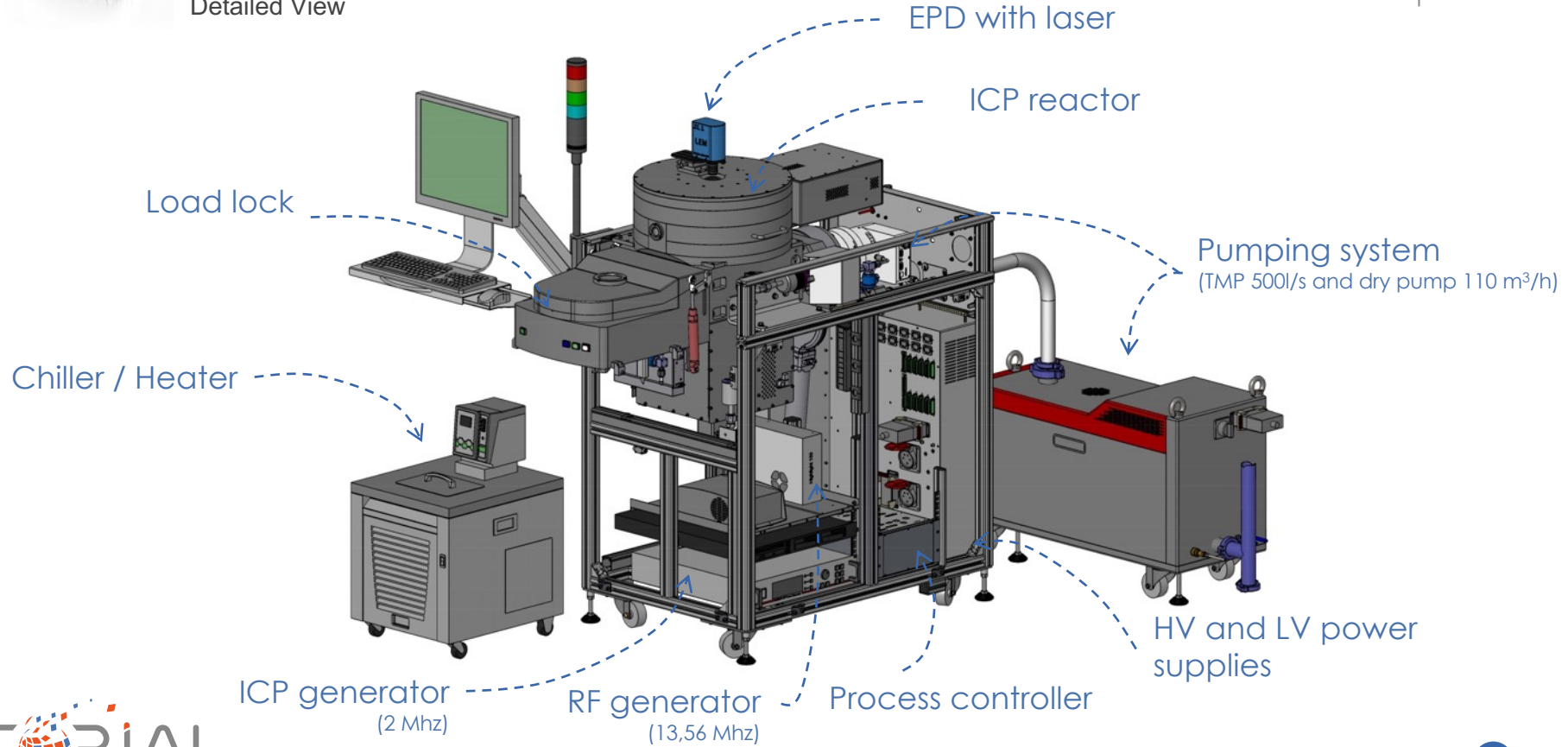
**THE MOST
COMPACT
MACHINE
ON THE MARKET**





SYSTEM DESCRIPTION

Detailed View





SYSTEM DESCRIPTION

7/19/18

Loading



< 180 s

LOADING TIME

Vacuum robot

FAST AND REPEATABLE LOAD AND UNLOAD

Shuttle

EASY EXCHANGE BETWEEN SUBSTRATE SHAPE AND SIZE

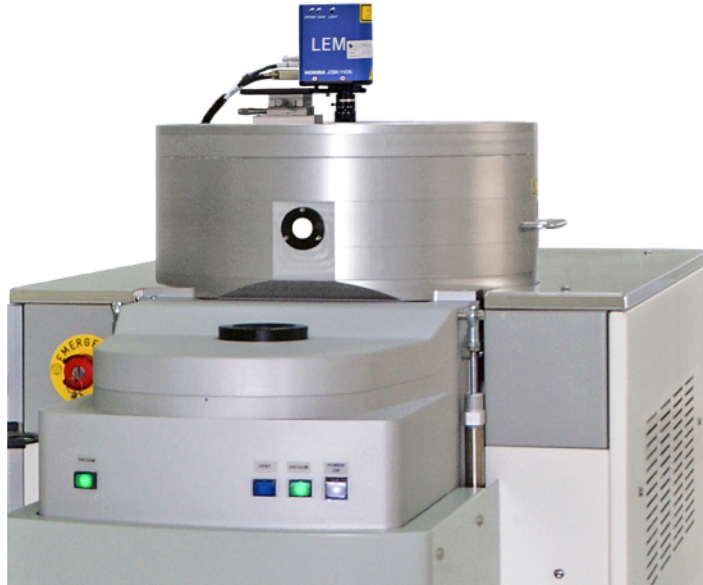
ICP SOURCE CORIAL 210IL



ICP SOURCE

CORIAL's Latest Generation of Reactor

FAST AND UNIFORM ETCHING



1. Load lock to run fluorinated and chlorinated chemistries in the same process recipe
2. Load lock for stable and repeatable process conditions
3. RF match box with matching range up to 2000 W
4. Uniform temperature control (from -50°C) for best repeatability
5. Hot walls ($>250^{\circ}\text{C}$) minimize polymer condensation for selective processes
6. Hot walls and retractable liner reduce clean time
7. Retractable liner and shuttle holding to minimize process cross-contamination



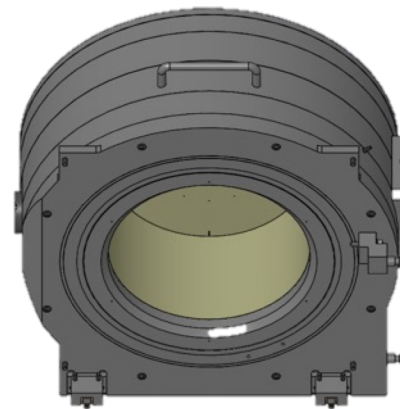
ICP SOURCE

Retractable Quartz Liner

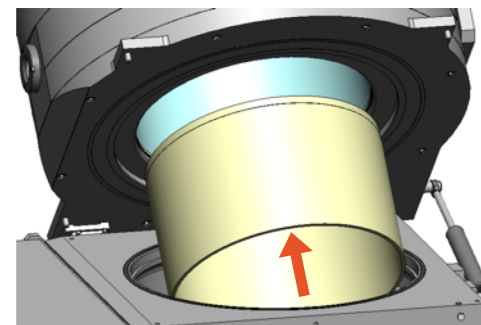
THE LINER FOR HARSH ICP-RIE PROCESSES



EASY LINER
replacement by a
single person



ZERO
CROSS
CONTAMINATION



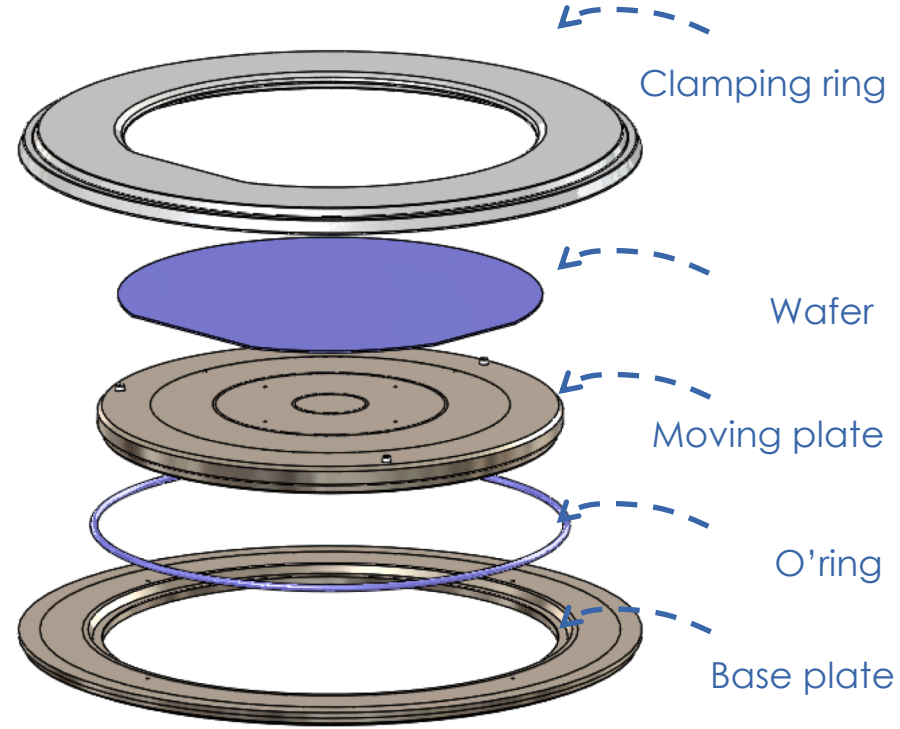
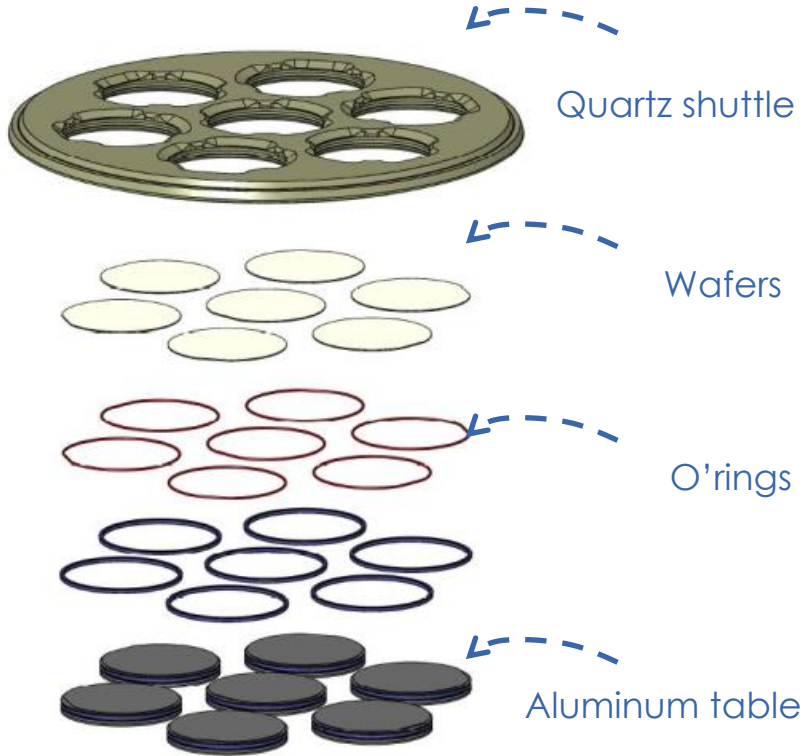
Corial 210IL DRIE Applications

SHUTTLE HOLDING APPROACH CORIAL 210IL



SHUTTLE HOLDING APPROACH

Portfolio

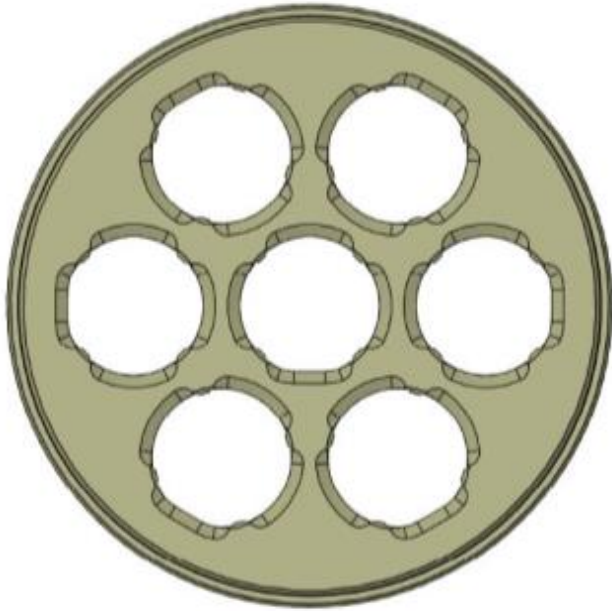


Guaranteed no wafer damage due to SOFT wafer clamping



SHUTTLE HOLDING APPROACH

Benefits



1. Quick adaptation to sample shape and size
2. Optimum process conditions with NO modification of process chamber
3. Limited cross contamination between processes by using dedicated shuttles
4. Shuttles for single wafer treatment: 1 x 2", 1 x 3", 1 x 4", 1 x 6", 1 x 8"
5. Shuttles for batch processing : 7 x 2", 3 x 3"
6. Customized shuttles are available (4" x 4", 5" x 5", etc)

USABILITY

CORIAL 210IL



PROCESS CONTROL SOFTWARE

COSMA



COSMA

CORIAL OPERATING SYSTEM FOR MACHINE

The simplest, most efficient software to develop processes, operate, and maintain CORIAL systems

DESKTOP APPLICATION

Process Editing | Process Adjustment | Process Operation | Process Tracability | System Maintenance



REMOTE CONTROL



MOBILE APPLICATION

Module & Process Follow-Up | Alarms & Warnings
Connected Users





REPROCESSING SOFTWARE

COSMA RS



DISPLAY UP TO

4

PARAMETERS
FROM A RUN

Simple and efficient
software to analyze process
runs and accelerate process
development

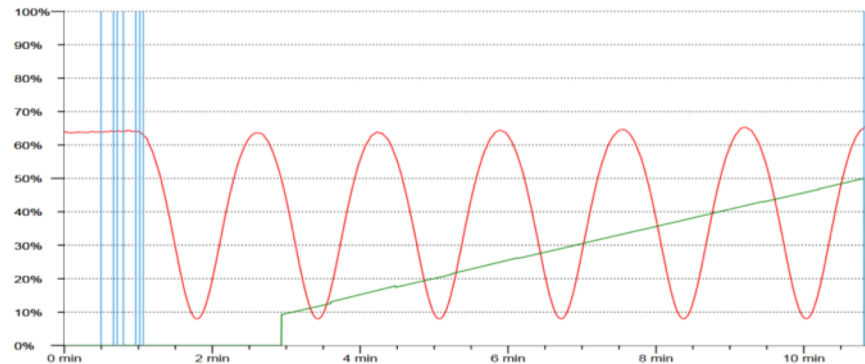
REMOTE
ANALYSIS OF RUNS

DRAG AND DROP
CURVES TO CHECK PROCESS
REPEATABILITY



END POINT DETECTION

7/19/18



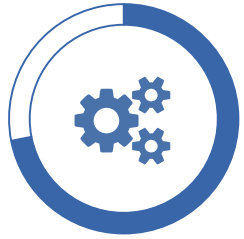
A CCD camera and laser diode, in the same measuring head, enables simultaneous visualization of the wafer surface and the laser beam impact on it. A 20 μm diameter laser spot facilitates the record of interference signals.

Real-Time etch rate measurement
Real-Time etched depth measurement



CORIAL 210IL

ICP-RIE equipment for deep etching applications



Wide process range for silicon, silicon carbide, glass, sapphire, and quartz deep etch



Support time-multiplexed processes (Bosch) in conventional dry etch reactor



Smaller wafer pieces up to full 200 mm wafer

